TOSHIBA Transistor Silicon PNP Epitaxial Type

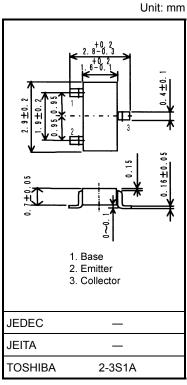
# 2SA2061

High-Speed Switching Applications DC-DC Converter Applications Strobe Applications

- High DC current gain:  $h_{FE} = 200 \text{ to } 500 \text{ (I}_{C} = 0.5 \text{ A)}$
- Low collector-emitter saturation voltage:  $V_{CE (sat)} = -0.19 \text{ V (max)}$
- High-speed switching: tf = 40 ns (typ.)

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V <sub>CBO</sub>	-20	V	
Collector-emitter voltage		V <sub>CEO</sub>	-20	V	
Emitter-base voltage		V <sub>EBO</sub>	-7	٧	
Collector current	DC	IC	-2.5	Α	
	Pulse	I <sub>CP</sub>	-4.0		
Base current		ΙΒ	-250	mA	
Collector power dissipation	t = 10 s	PC	1000	mW	
	DC	(Note)	625		
Junction temperature		Tj	150	°C	
Storage temperature range		T <sub>stg</sub>	−55 to 150	°C	



Weight: 0.01 g (typ.)

Note 1: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm<sup>2</sup>)

Note 2: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## **Electrical Characteristics (Ta = 25°C)**

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I <sub>CBO</sub>	$V_{CB} = -20 \text{ V}, I_E = 0$	_	_	-100	nA
Emitter cut-off current		I <sub>EBO</sub>	V <sub>EB</sub> = -7 V, I <sub>C</sub> = 0	_	_	-100	nA
Collector-emitter breakdown voltage		V (BR) CEO	I <sub>C</sub> = −10 mA, I <sub>B</sub> = 0	-20	_	_	V
DC current gain		h <sub>FE</sub> (1)	V <sub>CE</sub> = −2 V, I <sub>C</sub> = 0.5 A	200	_	500	
		h <sub>FE</sub> (2)	V <sub>CE</sub> = -2 V, I <sub>C</sub> = -1.6 A	100	_	_	
Collector-emitter saturation voltage		V <sub>CE (sat)</sub>	I <sub>C</sub> = -1.6 A, I <sub>B</sub> = -53 mA	_	_	-0.19	V
Base-emitter saturation voltage		V <sub>BE</sub> (sat)	I <sub>C</sub> = -1.6 A, I <sub>B</sub> = -53 mA	_	_	-1.10	V
Collector output capacitance		C <sub>ob</sub>	V <sub>CB</sub> = −10 V, I <sub>E</sub> = 0, f = 1 MHz	_	28	_	pF
Switching time	Rise time	t <sub>r</sub>	See Figure 1 circuit diagram.	_	70	_	ns
	Storage time	t <sub>stg</sub>	V <sub>CC</sub> ≈ −12 V, R <sub>L</sub> = 7.5 Ω	_	150	_	
	Fall time	t <sub>f</sub>	-I <sub>B1</sub> = I <sub>B2</sub> = −53 mA	_	40	_	

## Marking

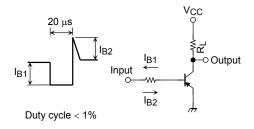
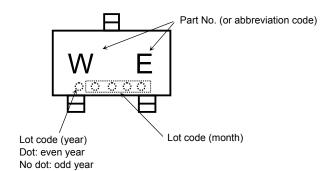
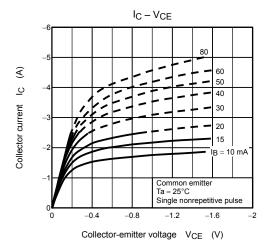
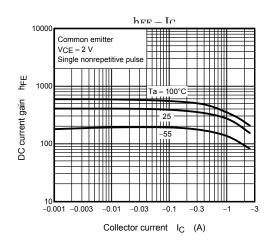
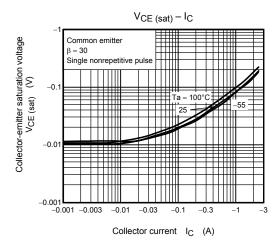


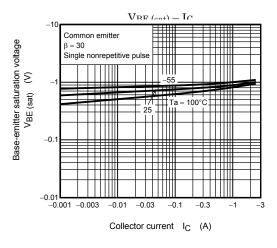
Figure 1 Switching Time Test Circuit & Timing Chart

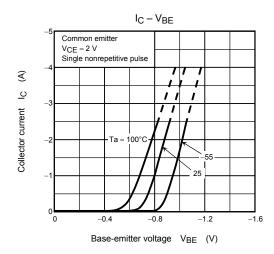




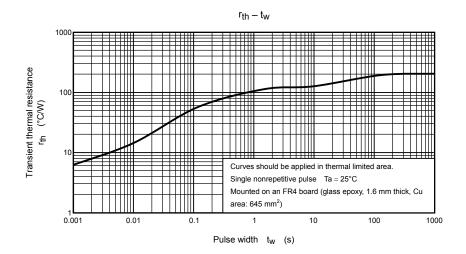


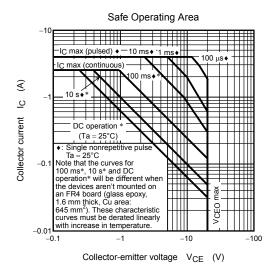






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